

P-Channel 40 V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^a	Q _g (Typ.)			
- 40	0.010 at V _{GS} = - 10 V	- 16.1	33 nC			
- 40	0.014 at V _{GS} = - 4.5 V	- 13.3	33110			

FEATURES

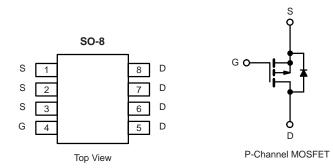
- Halogen-free According to IEC 61249-2-21 Definition
- 100 % R_g Tested
- 100 % UIS Tested

APPLICATIONS

Compliant to RoHS Directive 2002/95/EC



HALOGEN FREE



•	Load Switch
•	POL

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	- 40	V		
Gate-Source Voltage		V_{GS}	± 20	V	
	T _C = 25 °C		- 16.1		
Continuous Proin Current (T = 150 °C)	T _C = 70 °C	1 , [- 12.9		
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	l _D	- 10.2 ^{b, c}		
	T _A = 70 °C		- 8.2 ^{b, c}	^	
Pulsed Drain Current		I _{DM}	- 50	A	
Continous Source-Drain Diode Current	T _C = 25 °C		- 5.3		
Continous Source-Drain Diode Current	T _A = 25 °C	ls –	- 2.1 ^{b, c}		
Single Pulse Avalanche Current		I _{AS}	- 28		
Single Pulse Avalanche Energy L = 0.1 mH		E _{AS}	39	mJ	
	T _C = 25 °C		6.3		
Maximum Dawar Dissipation	T _C = 70 °C	1 , [4	w	
Maximum Power Dissipation	T _A = 25 °C	P _D	2.5 ^{b, c}	VV	
	T _A = 70 °C		1.6 ^{b, c}		
Operating Junction and Storage Temperature	T _J , T _{stg}	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	37	50	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	16	20] 0,00	

Notes:

- a. Based on T_C = 25 °C. b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under steady state conditions is 85 °C/W.



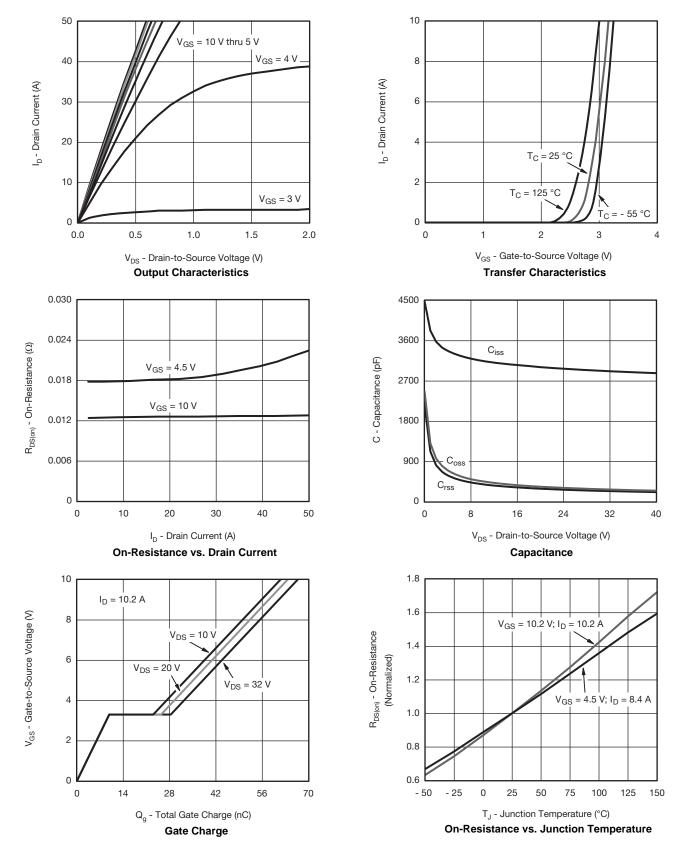
Parameter Symbol Test Conditions Min. Typ. Max. Unit Static	SPECIFICATIONS T _J = 25 °C, unless otherwise noted							
Drain-Source Breakdown Voltage V _{DS} V _{GS} = 0 V, I _D = · 250 μA - 40 V V V V _{DS} memperature Coefficient AV _{DS} (T) I _D = · 250 μA - 36 - 36 MV/°C MV/°C MV/°C MV/°C MV/°C MV/°C MV/°C MV/°C MV/°C S S MV/°C MV/°C MV/°C MV/°C S MV/°C MV/°C MV/°C S V MV/°C S V MV/°C S V MV/°C S V MV/°C MV/°C S V MV/°C S V D 2.25 V A 2.25 V A 2.25 V A 2.25 V A 2.25 V - 1.2 M - 1.2 M - 1.2 A - 2.5 V - 2.5 V - 2.5 V - 2.5 V A - 2.00 V - 2.5 V A - 2.00 V - 2.5 V A - 2.00 V - 2.5	Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
V _{DS} Temperature Coefficient ΔV _{DS} (T _J) I _D = -250 μA m/V/C V _{SS(P)} Temperature Coefficient ΔV _{SS(M)} V _{DS} = -250 μA -1.2 5 V Gate-Source Threshold Voltage I _{SS} V _{DS} = 0, V, V _{GS} = ±20 V ± ±100 nA Zero Gate Voltage Drain Current I _{DSS} V _{DS} = -40 V, V _{GS} = 0 V, T _J = 5°C -5 A On-State Drain Current ^a I _{D(m)} V _{DS} = -40 V, V _{GS} = 0 V, T _J = 5°C -5 A On-State Drain Current ^a I _{D(m)} V _{DS} = -40 V, V _{GS} = 0 V, T _J = 5°C -5 A On-State Drain Current ^a I _{D(m)} V _{DS} = -10 V, I _D = -10.2 A 0.010 A Or State Drain Current ^a V _{DS} = -15 V, I _D = -10.2 A 0.014 A Or State Drain Current ^a V _{DS} = -20 V, V _{GS} = 0 V, f = 1 MHz 330 D D D D P P P D A A A A A A	Static							
Vos(th) Temperature Coefficient ΔV _{GS(th)}	Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V, } I_D = -250 \mu\text{A}$	- 40			V	
$ \begin{array}{c} V_{\text{OS(N)}} \text{Temperature Coefficient} & AV_{\text{OS(M)}} \\ V_{\text{OSIM}} & V_{\text{DS}} = V_{\text{SS}}, I_{\text{D}} = -250 \ \mu\text{A} \\ \hline \text{Gate-Source Leakage} \\ \hline \text{Gate-Source Leakage} \\ \hline \text{Gate-Source Leakage} \\ \hline \text{I}_{\text{DSS}} \\ \hline \text{I}_{\text{DSS}$	V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I 250 HA		- 36		m\//°C	
	V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	η η = - 230 μΑ		5		mv/·C	
Vos = -40 V, Vos = 0 V	Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = -250 \mu A$	- 1.2		- 2.5	V	
Vos = -40 V, Vos = 0 V, T _J = 55 °C	Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
On-State Drain Current ^a I _{D(on)} V _{DS} = −50 V, I _J = −55°C −5 −5 −5 −5	Zero Gate Voltage Drain Current	I _{DSS}					μА	
Drain-Source On-State Resistance ^a R _{DS(on)} V _{GS} = -10 V, I _D = -10.2 A 0.010 0.014 0						- 5		
Drain-Source On-State Resistance RDS(on) VGS = -4.5 V, ID = -8.4 A 0.014 0.014 Forward Transconductance 9 Ig VDS = -15 V, ID = -10.2 A 37 S S	On-State Drain Current ^a	I _{D(on)}		- 25			Α	
Promard Transconductance Promard Transcondu	Drain-Source On-State Resistance ^a	R _{DS(on)}					Ω	
Dynamic Dyn			_				_	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $		9 _{fs}	V _{DS} = - 15 V, I _D = - 10.2 A		37		S	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Dynamic ^b	T		T		1	1	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Input Capacitance				3007			
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Output Capacitance		$V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		335		pF	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Reverse Transfer Capacitance	C _{rss}			291			
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Total Gate Charge	Q_g	V _{DS} = -20 V, V _{GS} = -10 V, I _D = -10.2 A				nC	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Gate-Source Charge	Q _{as}	V _{DS} = -20 V. V _{GS} = -4.5 V. I _D = -10.2 A			50		
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Gate-Drain Charge				15.7			
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Gate Resistance		f = 1 MHz	0.4	2	4	Ω	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Turn-On Delay Time				57	86		
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Rise Time	1 /	$V_{DD} = -20 \text{ V}, R_1 = 2.4 \Omega$		50	75	- - -	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Turn-Off Delay Time	t _{d(off)}	$I_D \cong -8.2 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_g = 1 \Omega$		40	60		
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Fall Time				17	26		
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	Turn-On Delay Time	t _{d(on)}			13	20	ns	
Fall Time t_f 9 18 Drain-Source Body Diode Characteristics Continuous Source-Drain Diode Current l_S $T_C = 25 ^{\circ}\text{C}$ -5.3 A Pulse Diode Forward Current l_{SM} -50 Body Diode Voltage V_{SD} $I_S = -8.2 \text{A}, V_{GS} = 0 ^{\circ}\text{V}$ $-0.8 -1.2 ^{\circ}\text{V}$ Body Diode Reverse Recovery Time t_{rr} $-8.2 \text{A}, \text{Moldt} = 100 \text{A/µs}, \text{T}_J = 25 ^{\circ}\text{C}$ -5.3 A Reverse Recovery Fall Time t_a -50	Rise Time		$V_{DD} = -20 \text{ V}, R_{L} = 2.4 \Omega$		11	20	-	
	Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 8.2 A, V_{GEN} = - 10 V, R_g = 1 Ω		45	68		
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Fall Time				9	18		
Pulse Diode Forward Current I_{SM} -50 Body Diode Voltage V_{SD} $I_S = -8.2 \text{ A}, V_{GS} = 0 \text{ V}$ $-0.8 -1.2 \text{ V}$ Body Diode Reverse Recovery Time t_{rr} $36 -54 - ns$ Body Diode Reverse Recovery Charge Q_{rr} Reverse Recovery Fall Time t_a $I_F = -8.2 \text{ A}, \text{ dI/dt} = 100 \text{ A/µs}, T_J = 25 °C$								
Pulse Diode Forward Current I_{SM} -50 Body Diode Voltage V_{SD} $I_S = -8.2 \text{ A}, V_{GS} = 0 \text{ V}$ $-0.8 -1.2 \text{ V}$ Body Diode Reverse Recovery Time t_{rr} $36 -54 \text{ ns}$ Body Diode Reverse Recovery Charge Q_{rr} Reverse Recovery Fall Time t_a $I_F = -8.2 \text{ A}, dI/dt = 100 \text{ A/µs}, T_J = 25 °C$ $-0.8 -1.2 \text{ V}$ $I_F = -8.2 \text{ A}, dI/dt = 100 \text{ A/µs}, T_J = 25 °C$ $-0.8 -1.2 \text{ V}$ $I_F = -8.2 \text{ A}, dI/dt = 100 \text{ A/µs}, T_J = 25 °C$ $-0.8 -1.2 \text{ N}$	Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			- 5.3	^	
Body Diode Reverse Recovery Time t_{rr} Body Diode Reverse Recovery Charge Q_{rr} Reverse Recovery Fall Time t_a $I_F = -8.2 \text{ A, dI/dt} = 100 \text{ A/µs, T}_J = 25 \text{ °C}$ 20 ns	Pulse Diode Forward Current	I _{SM}				- 50	A	
Body Diode Reverse Recovery Time t_{rr} Body Diode Reverse Recovery Charge Q_{rr} Reverse Recovery Fall Time t_a $I_F = -8.2 \text{ A, dI/dt} = 100 \text{ A/µs, T}_J = 25 \text{ °C}$ 20 ns	Body Diode Voltage	V_{SD}	I _S = -8.2 A, V _{GS} = 0 V		- 0.8	- 1.2	V	
Reverse Recovery Fall Time t_a $I_F = -8.2 \text{ A, dl/dt} = 100 \text{ A/}\mu\text{s, } I_J = 25 \text{ °C}$ 20	Body Diode Reverse Recovery Time				36	54	ns	
Reverse Recovery Fall Time t _a 20	Body Diode Reverse Recovery Charge	Q _{rr}			41	62	nC	
Reverse Recovery Rise Time t _b ns	Reverse Recovery Fall Time	t _a	- 1 _F = - 6.2 A, αι/αι = 100 A/μs, 1 _J = 25 °C		20			
	Reverse Recovery Rise Time	t _b	1		16		- ns	

Notes:

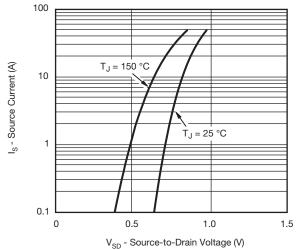
- a. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 %.
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

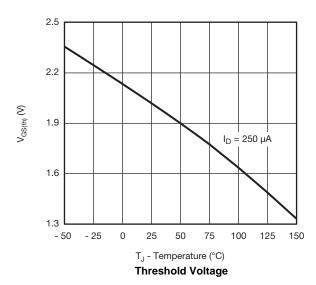






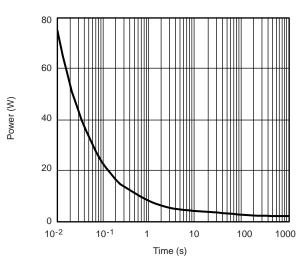




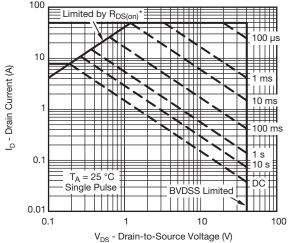


0.05 0.04 0.03 0.02 0.01 $T_{J} = 125 \, ^{\circ}\text{C}$ $T_{J} = 25 \, ^{\circ}\text{C}$ 0.01 V_{GS} - Gate-to-Source Voltage (V)

On-Resistance vs. Gate-to-Source Voltage



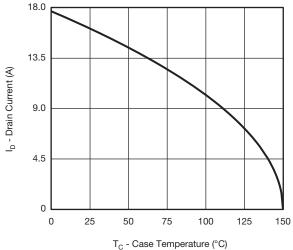
Single Pulse Power (Junction-to-Ambient)



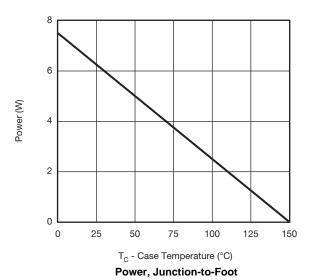
 $^{*}V_{GS}$ > minimum V_{GS} at which $R_{DS(on)}$ is specified

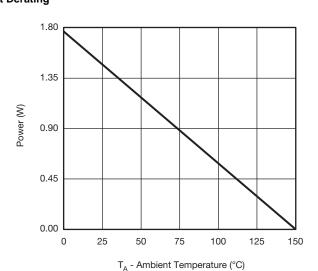
Safe Operating Area, Junction-to-Ambient





Current Derating*

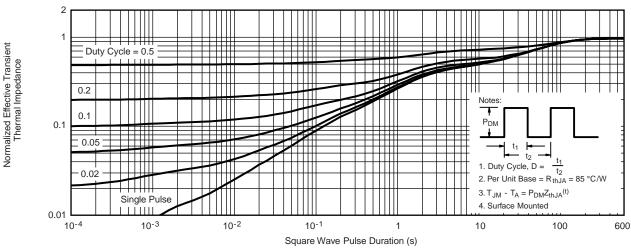




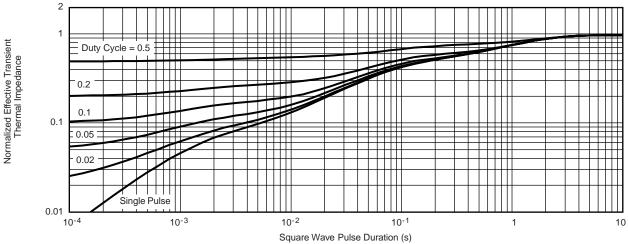
Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012







	MILLIMETERS		INCHES		
DIM	Min	Max	Min	Max	
Α	1.35	1.75	0.053	0.069	
A ₁	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
FCN: C-06527-Rev I 11-Sep-06					

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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